제 32회 한국반도체학술대회
The 32nd Korean Conference on Semiconductors

2025년 2월 12일(수)-14일(금) | 강원도 하이원리조트

Future Normal in Semiconductor

2025-02-14(금), 09:00-10:45
좌장: 추후업데이트 예정

G. Device & Process Modeling, Simulation and Reliability 분과
[FK1-G] Reliability & Packaging Simulation

FK1-G-1 09:00-09:15	**Insertion of Protective Layer for Enhancing Effect of N_2O Plasma Treatment on NBS Stability in IGZO TFTs** Seungyoon Shin, Jinkyu Lee, Hyunjin Choi, Seong-In Cho, and Soo-Yeon Lee Department of Electrical and Computer Engineering, Inter-university Semiconductor Research Center, Seoul National University
FK1-G-2 09:15-09:30	**Degradation modeling of positive bias stress reliability in a-IGZO TFTs considering the effects of oxygen and hydrogen** Do Hun Kim[1], Seung Joo Myoung[1], Dong Hyeop Shin[1], Jung Rae Cho[1], Donguk Kim[1], Changwook Kim[1], Dae Hwan Kim[1], Narae Han[2], Jee-Eun Yang[2], Younjin Jang[2], and Sangwook Kim[2] [1]School of Electrical Engineering, Kookmin University, [2]Samsung Advanced Institute of Technology, Samsung Electronics
FK1-G-3 09:30-09:45	**Comprehensive Analysis of Proton Collision Effects in SOI MOSFETs using Transient and Steady-State Responses** Hwan Jin Kim[1], Haesung Kim[1], Hyojin Yang[1], Yubin Choi[1], Sujong Kim[1], Hyunwook Jeong[1]Sung-Jin Choi[1], Dae Hwan Kim[1], Dong Myong Kim[2], Sung Yun Woo[3], and Jong-Ho Bae[1] [1]School of the Electronic Engineering, Kookmin University, [2]Department of Advanced Technology, DGIST,[3]School of Electronic and Electrical Engineering, Kyungpook National University
FK1-G-4 09:45-10:00	**Uncovering Novel Time Exponent Variations in PBTI of a-IGZO Transistors via a 1 µs Ultrafast On-the-Fly Technique** Taewon Seo[1], Changeon Jin[1], and Yoonyoung Chung[1,2,3] [1]Department of Electrical Engineering, POSTECH, [2]Department of Semiconductor Engineering, POSTECH, [3]Center for Semiconductor Technology Convergence, POSTECH
FK1-G-5 10:00-10:15	**Analysis of Proton?Induced Electrical Degradation in a-IGZO TFTs under Aerospace Environments** Yubin Choi[1], Haesung Kim[1], Hyojin Yang[1], Junseong Park[1], Hyunwook Jeong[1],Sujong Kim[1], Hwan Jin Kim[1], Sung-Jin Choi[1], Dae Hwan Kim[1], Dong Myong

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	Kim[2], Sung Yun Woo[3], and Jong-Ho Bae[1] [1]School of the Electronic Engineering, Kookmin University, [2]Department of Advanced Technology, DGIST, [3]School of Electronic and Electrical Engineering, Kyungpook National University
FK1-G-6 10:15-10:30	**Data-driven Method for Predicting Thermo-mechanical Property Maps of Patterned Semiconductor Packages Using Machine Learning** Jeong-Hyeon Park, Sung Jun Kang, and Eun-Ho Lee Sungkyunkwan University
FK1-G-7 10:30-10:45	**Development of an In-House Finite Element Method Simulator for Static Structural Analysis of a Warped Wafer** Sung-Min Hong School of Electrical Engineering and Computer Science, GIST